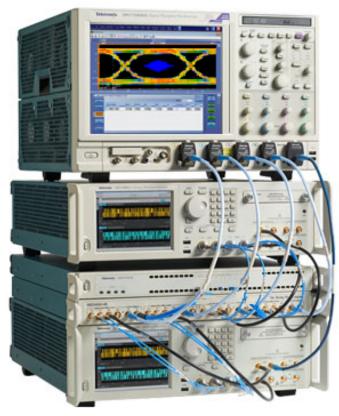
Tektronix[®]

D-PHY Transmitter Test, Receiver, and Protocol Solutions

D-PHYTX, D-PHYXpress, SR-DPHY, and Moving Pixel Datasheet



Tektronix D-PHYTX, D-PHYXpress, SR-DPHY, and Moving Pixel D-PHY Protocol solution provides one stop comprehensive solution for conformance and characterization of Transmitter, Receiver, and Protocol test requirement as per MIPI standards. Tektronix D-PHYTX automated solution provides easy way to debug and characterize D-PHY data links. D-PHYTX allows you to select all the electrical and timing measurements defined in MIPI D-PHY, up to v1.2 specification. The D-PHYXpress software enables flexible and intuitive receiver testing of D-PHY v1.2 specification designs with AWG70000 Series Arbitrary Waveform Generator. ¹

Key features

Transmitter testing:

- Test time
 - Fully automated solution: Performs D-PHY transmitter test with single-button click, seamlessly across High Speed (HS), Low Power (LP), Low Power-High Speed (LP-HS) and Ultra-Low Power State (ULPS) sequences in the D-PHY signal.
 - Allows to select individual test or group-wise tests through the tree structure.
 - RF Switch support to handle multi-lane test with zero manual intervention.
- 100% test coverage as per D-PHY v1.2, CTS v1.2
 - Performs all fully-automated tests, including Bus Turn Around (BTA) and Ultra-Low Power State (ULPS) measurements, as per D-PHY specifications up to v1.2.
- Debug features
 - Modify limits of test parameters in TekExpress for debug and characterization.
 - Provides DPOJET based setup files to debug the root cause analysis of failures.
- Measurement accuracy
 - D-PHYTX application handles multitude scenarios like Continuous or Burst mode, Termination variations, and varying idle time.
- Transmitter conformance test and beyond
 - Custom limits to perform margin testing
 - Performs characterization by running TekExpress application in continuous mode and collect the data.
- Signal access
 - P7700 Series High Impedance TriMode probe (D-PHY Essentials only) designed especially for MIPI application, that requires low loading, single-ended/differential measurements.
 - Provides TekFlex[™] accessories for flexible probing
- Offline/Remote analysis
 - Analyze live or pre-acquired waveforms
 - Allows remote execution of tests

See the host system requirements in the Ordering Information section.

Receiver testing:

- Simplified Receiver test setup
 - Single setup to generate signal for D-PHY and C-PHY
 - Easy to calibrate and provide repeatable result
 - Direct synthesis method helps to create all types of stress with single box.
- Test Coverage

100% Test coverage: D-PHYXpress application allows you to create D-PHY standard conformant test signals as per MIPI D-PHY v1.2 and v2.0 specifications.

Signal Fidelity

Best in class AWG70000 Series with sampling rate of 50 GS/s with 10 bit vertical resolution, to provide best signal fidelity for D-PHY signal generation.

• Ease of Use

D-PHYXpress provides batch processing to create multiple test scenarios for rigorous test requirements.

- Receiver conformance test and beyond
 - D-PHYXpress application provides a platform for you to create wide range of stimuli to test the device beyond specification.
 - You can program Data to Clock timing, Rise time and Fall time of Data/Clock, Program ESC, LP Command along with Programmable Stress as mentioned below:
 - HS mode stressors
 - Random Jitter and Deterministic Jitter
 - Embed Insertion Loss and De-emphasis
 - Spread Spectrum Clocking
 - Dynamic Skew (D-PHY)
 - LP mode stressors
 - e_{Spike} and Minimum Pulse T_{MIN-RX}
 - Set up/hold time tolerance
 - Real-time skew control
- Offline signal generation

D-PHYXpress application can work in offline mode or from PC to control AWG remotely and generate D-PHY signals.

Scope based DSI-1 and CSI-2 Protocol Decode:

- Decodes DSI and CSI-2 buses in Low Power and High Speed states.
- Decodes both short packets, long packets and communications types such as Bus Turn Around (BTA), Escape Mode Commands, and Low Power data.
- Decodes the DCS command, ECC, checksum, data type, packet data, and others.
- Displays event table, search, and error indicators.
- Indicates missing sync, ECC, and checksum errors.

Moving Pixel D-PHY Protocol Generator and Decoder:

- D-PHY Protocol Generator
 - Supports up to D-PHY v1.2, CSI v1.2, and DSI v1.2 protocols.
 - Standalone instrument with simplified setup and operation.
 - Supports MIPI D-PHY signaling up to 2.5 Gbps-per-lane, for 1-4 lanes.
 - Provides automated video sequence construction according to the user-defined frame timing.
 - Supports command insertion during looping video upon user command.
 - Provides extensive scripting and macro-capability (macros can now contain video mode frames).
- D-PHY Protocol Decoder
 - Monitors MIPI D-PHY traffic up to 2.5 Gbps-per-lane, for 1-4 lanes.
 - Standalone instrument with simple setup and operation
 - Provides Sniff Mode (high-Z) and Receive Mode (SMA, terminated) interfaces.
 - Supports acquisition of contiguous D-PHY traffic using 1 GB capture memory.
 - Provides Protocol Packet triggering, LP sequencing and State triggering, and ECC/CRC/Burst Error triggering.
 - Provides real-time statistics: Bus activity, measured bit-rate, packet counts, and ECC/CRC error counts, etc.
 - Acquires, decodes, and displays CSI2 v1.2, DSI v1.2 protocol packets and D-PHY 1.2 signaling states (earlier standards are also supported).
 - Provides extensive search and display filtering capabilities.
 - $\circ \quad \mbox{Provides extensive RPC remote-control capability}.$

Applications

D-PHY testing for:

- Automotive camera and display
- Mobile camera and display
- D-PHY interface design
- DSI-1 or CSI-2 verification
- System validation and integration
- Manufacturing test

Transmitter testing

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I.3.1 Data Lane HS Entry: Data Lane TLPX Value II.3.2 Data Lane HS Entry: THS-PREPARE Value		Select individual measurement to view its description	
- 🗹 1.3.2 Data Lane HS Entry: THS-PREPARE Value			Show Schematic
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D-PHYTX application

Single-button fully automated D-PHY testing

The Tektronix TekExpress® (TEKEXP) Automated Test software runs on Windows 7 operating system.

TekExpress software ordered with Option D-PHYTX provides an automated, simple, and efficient way to test D-PHY Transmitter interfaces and devices consistent to the requirements of the D-PHY Conformance Test Specification revision up to v1.2.

Automated testing – save time and resources

D-PHYTX allows you to select the desired tests to run and test the multiple lanes that to be tested. The automated solution, allows you to focus on design and debug of the measurements.

Setup test execution and reporting of measurements

Setup and test execution is simple with the TekExpress D-PHYTX software. The oscilloscope is controlled through the TekExpress automation framework. The TekExpress software provides a Graphical User Interface (GUI) and provides an intuitive workflow through setup and testing. D-PHYTX application provides GUI to select Test specification, Tree structure of HS, LP, HS-LP tests as per specifications, and Configuration for test condition.

Setting up the bench

You can view the schematic of the selected test with a push of a button. It also displays graphical representation of the test connection to avoid human errors.

Pass/fail report

The report tab provides a view of test results along with pass or fail status, test margin, and images supporting the test results for each lane of the DUT.

Enabling innexation	D.5	HY Transmit	ter Signal Ch	racteris	tics Test Re	nort					
	0-1	The transmit			ues lest ite	pon					
DUT ID : DUT001 Date/Time : 6/9/2015 23:07			Device Type : Execution Time	D-PHY CSI-2 10 Min					TS Version Compliant	CTS 12 Base Spec 12	
									Test Result		
Scope Moder : MIX/2004C	Bcope Berlai Namber : G	100114			Scops Filtr Verplan :	750DEVIRAL	01	SPC Fa	ton Calibration	FASTINGS	
Chill Poter Model : 1X	Off Rote Sessi Number N	A			Talifignese Version	DAW 3301	72, Frankers	#k 200251			
CH2 Probe Modal : 1X	Ord Prote SenalHumber: N										
CFCI Pt obe Model : 1X	G-B Prote Setal Number : N	4									
CH4LPt obe Model : 1X	OH Pote Setal Number : N	κ									
Dierall Summary	Late 3	Late 4	CixkLand		Computed (IKris)	1					
Status Pass NA	NA NA	NA NA	Pres		NA NA	1					
Lane1	and the second s						Result	Mode	Time		
	(Spec 1.2) Data Lane UP- TX Thevanin Output High	>= 0.95	1 1255000000	c= 1.3	0.1768.0.1712		Pass			Min value for DP = 1.1 Max value for DP = 1.1	
 1 Data Lane LP-TX Therenin Output High Level Vollage (VOH) 	Level Vallage DP (Spec. 1.2) Data Lans LP- TX Thevenin Output High Level Vallage DN	>= 0.96	1.1292900900	<= 1.3	0.1792, 0.1706	v	Pass	Yes	10 Sec.	Region count for DP- Minivature for DN = 1.1 Maximize for DN = 1.1 Region count for DN =	
12 Data Lane UP-TX Thevenin Output Low	Data Lane LP-TX Thevenin Output Low Level Voltage DP	>= -50	3 500000000	<= 50	53.5, <i>4</i> 6.6	-	P865	Yes		Min value for DP = 0. Min while for DP = 0.0030, Region count for DP= 3 Min value for DN = 0. Min value for DN = 0.0036, Region count for DN= 1	
Level Vollage (VOL)	Data Lane LP-TX Thevenin Output Low Level Voltage DN	i>≈ -50	3.0000000000	<= 50	53.6, 46.4	197	Pass	1 165	6 S 80 Ma		
	Data Lane Rise Time DP		9.0726000000	<* 25	15.928		Pass			Minivelue for DP = 9.04 009, Mar value for DP 9 12e-009, Region cour	
13 Data Lane J P-TX 155-855 Rise Time	Data Lane Rise Time DN		9 1222223233	<= 25	15.8987	nS	P365	Yes	9 Sec	for DP= 5 Min value for D = 9.04e-000, Max value f DN = 9.20-009, Rogion count for DN= 6	

Pass/fail report

Beyond conformance - D-PHY Transmitter testing with D-PHY Essentials

DPOJET software with Option D-PHY provides the essential set of D-PHY Transmitter measurements with greater flexibility in the test setup. This option allows engineers to test device beyond conformance.

The following table outlines the key benefits from the DPOJET Option D-PHY and the TekExpress Option D-PHYTX software solution.

Key Benefits from D-PHY Essentials and D-PHYTX Automated Solution

Feature	Option D-PHY (D-PHY Essentials)	Option D-PHYTX (D-PHYTX Automated Solution)
Prerequisite tools	DPOJET Timing and Analysis	TEKEXP Automation
Automatic measurement selections based on device ID, test group, and selected probes		<i>✓</i>
Single-button execution for all measurements		1
Configurable setup and editing of test limits	1	1
Detailed or summary reports	Detailed only	Detailed and Summary
Automatically save test reports and waveforms		1
Re-analyze prerecorded waveforms	1	1
D-PHY specific user interface		\checkmark
Conformance test specification revision	up to v1.2	up to v1.2

P7700 probe (D-PHY Essentials only) for MIPI D-PHY

MIPI D-PHY application needs special type of probing as it operates in different impedance mode in High Speed and Low Power mode. In High Speed mode, D-PHY signals operate in terminated mode with differential signaling. In Low Power mode, D-PHY signal is operated in unterminated mode with single-ended signals. MIPI D-PHY has two main requirements for probing:

- Provide high impedance
- Differential and single-ended mode

P7700 Series probe (D-PHY Essentials only) provides active buffer tip designed for Low Probe loading few millimeters from end of tip to provide best signal fidelity for MIPI D-PHY application along with flexible connectivity options.

With TriMode probing, probe setup makes differential, single-ended, and common mode measurements accurately. This unique capability allows you to work more effectively and efficiently, switching between differential, single-ended and common mode measurements without moving the probe's connection points.



You can be confident in the signal fidelity of your measurements. The innovative new probe design uses SiGe Technology to provide the bandwidth and fidelity needed today and in the future.

The P7700 Series probe (D-PHY Essentials only) architecture provides:

- An active buffer amplifier on the tips with the probe input only 3.2 mm from the input
- · Excellent step response and low insertion loss up to 20 GHz
- Low-DUT loading with 100 kΩ (DC) and 0.4 pF (AC) performance
- High CMRR
- Low noise

Switch Matrix support

The D-PHY application supports Switch Matrix option which enables fully automated testing for multi-lane D-PHY Transmitter test.

。 。	1 2 Ch 1		Ch 2		
-	DP .		DN -		
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lap the i	nput types to t	he source ch		F:	
	-		Searce		

DPHY TEKXpress - Switch configurator

Advantages of Switch Matrix for D-PHY application:

- Multilane Testing: Switch Matrix eliminates reconnection and reduces errors through automating test setup for each lane of a multilane D-PHY bus.
- De-embed loss of Switch using S-Parameters to perform accurate measurements.

Test coverage

D-PHYTX application provides 100% test coverage as per D-PHY v1.2. For more details, refer to the *Transmitter test specification* table.

Receiver testing

The D-PHYXpress plugin creates D-PHY signals for High Speed, High Speed Burst, and Low Power content with worst-case impaired input signals.

Receiver test solution follows the below steps:

- Generate test signal to emulate the transmitter including channel and noise impairments.
- Calibrate the signal as per the CTS requirement.
- Setup the Device for the receiver test.
- Determine the Bit Error Rate in the given test condition.

The D-PHYXpress application addresses the capabilities in the following step 1 and step 2:

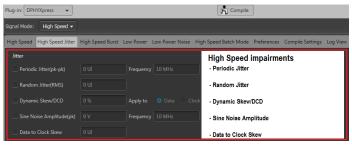
Step 1: Generate test signal to emulate the transmitter including channel and noise impairments

The D-PHYXpress supports waveform generation for High Speed, Low Power, and Low Power-High Speed (LP-HS) mode as per D-PHY specification up to v2.0.

High Speed mode: The D-PHY v2.0 specification data rate is up to 4.5 Gbps in High Speed mode. As per CTS, you need to emulate the channel effect in High Speed mode. D-PHYXpress application allows you to edit the data rate, rise time, pattern type, voltage level, and impairments to emulate the channel effect.

Plug-in: DPHYXpress 👻)
Signal Mode: High Speed -	
High Speed High Speed Jitter High Speed Burst Low Power Low Power Noise High Speed Batch Mode Pref	erences Compile Settings Log View
Base Pattern Base Pattern PR857 Data Rate 1.5 Gbps Bt/9b Encode	High Speed waveform generation - Base pattern
Voltage Levels	- Data Rate: 60 Mbps to 4.5 Gbps
VOD VCM Data 150 mV 150 mV S Apply data voltage levels to clock	- Voltage levels for Data and Clock
Clock 150 mV 150 mV 150 mV	- Rise/Fall time
HS Continuous Clock through Marker Analog to Marker Deby 0 s	

In High Speed mode, you can add various channel effect such as: Periodic Jitter (Pj), Random Jitter (Rj), Dynamic Skew, Sine Noise Amplitude, Data to Clock Skew, De-Emphasis, S-Parameter file of Channel for Data and Clock, and SSC on Clock signal.



High Speed Jitter - Jitter

De-Emphasis 0 dB		- De-Emphasis
High Speed Jitt	ter - De-Emphasis	
Embed Channel		
C O FLT Files		Embed Channel: Add ISI using Filter File
🗸 🗹 Data		
Positive Signal		C Apply Positive Signal filter file to Negative Signal
Negative Signal		
Clock		
Positive Signal		Piper Signal filter file to Negative Signal 🛛 🖉
Negative Signal		8

High Speed Jitter - Embed Channel

 S-Parameter Fi Embed Bandwidth Limit - 		ISI effe	ct using S-Parameter
	6		
	- @		
	-63		
	-63		

High Speed Jitter - S-Parameter

Spread Spectrum Cloc	king	
		Spread Spectrum Clocking (SSC)
Modulation Rate		
Deviation		



Low Power mode: The D-PHY v2.0 specification data rate is up to 100 MHz in Low Power mode. The D-PHYXpress application allows you to edit data rate, rise time, pattern type, voltage level, and impairments to emulate the channel effect.

Plug-in: DPHYXpress 🔻		Compile
Signal Mode: Low Power 👻		
High Speed High Speed Jitter	High Speed Burst Low Power Lo	ow Power Noise High Speed Batch Mode Preferences Compile Settings Log View
Base Pattern		Low Power waveform generation
Pattern PRBS7 🔹		- Base Pattern
Signal Data Rate 20 MHz	TLPX 50 ns	- Data Rate
Voltage Levels Thevenin High	Thevenin Low	- Voltage Levels
Positive 1V Negative 1V	50 mV S0 mV	positive voltage levels to regative
Rise/Fall Rise/Fall Time(0-100%) 0 U		



The D-PHY v2.0 specification requires Sine/Square noise with eSpike noise.

High Speed

LP-HS mode: The D-PHYXpress allows you to add Sync Word as per the specification with timing parameters for Data and Clock.

Plug-in: DPHYXpress 🔻			Compile
Signal Mode: Low Power - High Speed -			
High Speed High Speed Jitter High Speed	Burst Low Powe	r Low Power Noise	High Speed Batch Mode Preferences Compile Settings Log View
Create Burst (Applicable in LP-HS signal n	node) x 8 = 8		Low Power - High Speed High Speed Burst Create Burst: - Sync Word
Clock Mode Burst -			- Clock Mode: Burst/Continuous
Data	Clock		
THS TRAIL 64 ns	TCLK TRAIL	50 ns	
THS PREPARE 66 ns	TCLK PREPARE	60 ns	
THS REOT 20 ns		100 ns	
THS ZERO 150 ns		160 ns	
		20 ns	
		20 ns	
	TCLK ZERO	250 ns	



Step 2: Calibrate the signal as per CTS requirement

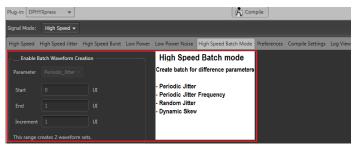
Calibration of signal impairments provides calibration routines that are D-PHY standard specific. The objective of calibration is to compensate the patterns for specific jitter parameters. The typical parameters are Random, Periodic Jitter, and Amplitude. The procedure sequences through all the patterns and each pattern is calibrated independently. These values are used for the Jitter controlled generation of patterns and are injected into the DUT during loopback.

Test coverage

For more details, refer to the Receiver test specification table.

Batch mode

Batch mode allows you to create a library of compiled waveforms with incremental Jitter value with a single click.



High Speed Batch mode

Scope-based decode for DSI-1 and CSI-2

The SR-DPHY application option enables decoding of DSI-1 and CSI-2 buses. SR-DPHY displays all the decoded components of short packets, long packets, and other communications types such as Bus Turn Around (BTA) and Escape Mode commands. In addition, DCS packets decode the DCS command.



MSO70000C display of decoded digital-channel of a packed pixel stream, 24-bit RGB 8-8-8 format packet



MSO70000C display checksum error of decoded analog-channel of a packed pixel stream

Low-power states: High Speed (LPS HS), Escape (LPS escape), and Bus Turn Around (LPS BTS).

High Speed: Start-of-Transmission (SoT), Short Packets (SP), Long Packets (LgP), and End of Transmission (EoT).

Escape: Escape command (Low-Power data, Ultra-Low Power, Reset trigger, Tearing effect, and Acknowledge) and Low-Power data – will decode as packet data (SP/LgP).

Short packets: Data Type, Virtual Channel, Packet data byte 1, Packet data byte 2, and Error Correcting Code.

Long packets: Data Type, Virtual Channel Word Count, Payload (decoded as pixels or bytes depending upon data type), and Error correcting code.

In addition to decoding DSI-1/CSI-2 acquisitions, SR-DPHY also searches through long acquisitions to find all occurrences of the following packet types:

- Short Packets (specify VC, DT, direction, and packet data values)
- Long Packets (specify VC, DT, direction, WC, and data payload including pixel values)
- Start-of-Transmission (SoT), Stop, End-of-Transmission (EoT), Bus Turn Around (DSI-1 only), Escape mode, ECC warning, ECC error, and Checksum error.

Moving pixel protocol solution

For more information on Moving Pixel solution, refer to http://www.movingpixel.com/main.pl?about.html.

Required equipment for D-PHY Transmitter and Receiver testing

For a complete list of required equipment, visit http://www.tek.com/mipi-0.

Specifications

All specifications apply to all models unless noted otherwise.

Transmitter test specification

D-PHY conformance specification Revision 1.2 Measurements Both High Speed and Low Power modes, including ULPS and BTA. Group 1 tests Data lane LP-TX signaling 1.1.1 Data lane LP-TX Thevenin output high level voltage (VOH) 1.1.2 Data lane LP-TX Thevenin output by level voltage (VOL) 1.1.3 Data lane LP-TX Thevenin output low level voltage (VOL) 1.1.4 Data lane rise time 1.1.5 Data lane LP-TX slew rate versus CLOAD (\deltaV/δISR) 1.1.6 Data lane LP-TX pulse width of exclusive-OR clock (TLP-PULSE-TX) 1.1.7 Data lane LP-TX signaling 1.2.1 Clock lane LP-TX signaling 1.2.2 Clock lane LP-TX signaling 1.2.3 Clock lane LP-TX signaling 1.2.4 Clock lane LP-TX signaling 1.2.5 Clock lane LP-TX signaling 1.2.4 Clock lane LP-TX signaling 1.2.5 Clock lane LP-TX signaling 1.2.4 Clock lane LP-TX signaling 1.2.5 Clock lane LP-TX signaling 1.2.6 Clock lane LP-TX signaling 1.2.7 Clock lane LP-TX signaling 1.2.8 Clock lane FIB 1.2.9 Clo	
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1.3.2 Data lane HS entry: THS-PREPARE value	
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1.3.4 Data lane HS-TX differential voltages (VOD(0), VOD(1))	
1.3.5 Data lane HS-TX differential voltage mismatch (ΔVOD)	
1.3.6 Data lane HS-TX single ended output high voltages (VOHHS(DP),VOHHS(DN))	
1.3.7 Data lane HS-TX common-mode voltages (VCMTX(1),VCMTX(0))	
1.3.8 Data lane HS-TX common-mode voltage mismatch (ΔVCMTX(1,0))	
1.3.9 Data lane HS-TX dynamic common-level variations between 50-450 MHz (ΔVCMTX(LF))	
1.3.10 Data lane HS-TX dynamic common-level variations above 450 MHz (ΔVCMTX(HF))	
1.3.11Data lane HS-TX 20%-80% rise time (tR)	
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1.3.13 Data lane HS exit: THS-TRAIL value	
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1.3.15 Data lane HS exit: TEOT value	
1.3.16 Data lane HS exit: THS-EXIT value	
Group 4 tests Clock lane HS-TX signaling	
1.4.1 Clock lane HS entry: TLPX value	
1.4.2 Clock lane HS entry: TCLK-PREPARE value	

Transmitter test specification

1.4.3	Clock lane HS entry: TCLK-PREPARE + TZERO value
1.4.4	Clock lane HS-TX differential voltages (VOD(0), VOD(1))
1.4.5	Clock lane HS-TX differential voltage mismatch (ΔVOD)
1.4.6	Clock lane HS-TX single ended output high voltages (VOHHS(DP),VOHHS(DN))
1.4.7	Clock lane HS-TX common-mode voltages (VCMTX(1),VCMTX(0))
1.4.8	Clock lane HS-TX common-mode voltage mismatch (ΔVCMTX(1,0))
1.4.9	Clock lane HS-TX dynamic common-level variations between 50-450 MHz (ΔVCMTX(LF))
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1.4.11	Clock lane HS-TX 20%-80% rise time (tR)
1.4.12	Clock lane HS-TX 80%-20% fall time (tR)
1.4.13	Clock lane HS exit: TCLK-TRAIL value
1.4.14	Clock lane HS exit: 30%-80% Post-EoT rise time (TREOT) value
1.4.15	Clock lane HS exit: TEOT value
1.4.16	Clock lane HS exit: THS-EXIT value
1.4.17	Clock lane HS clock instantaneous (UIINST)
1.4.18	Clock Lane HS Clock Delta UI (ΔUI)
Group 5 tests	HS-TX Clock-to-Data lane timing
1.5.1	HS entry TCLK-PREValue
1.5.2	HS exit TCLK-POST value
1.5.3	HS clock rising edge alignment to first payload bit
1.5.4	Data-to-Clock skew (TSKEW (TX))
1.5.5	Initial HS Skew Calibration Burst (TSKEWCAL-SYNC, TSKEWCAL)
1.5.6	Periodic HS Skew Calibration Burst (TSKEWCAL-SYNC, TSKEWCAL)
Group 6 tests	LP-TX INIT, ULPS and BTA requirements
1.6.1	INIT: LP-TX initialization period (TINIT,MASTER)
1.6.2	ULPS entry: verification of clock lane LP-TX ULPS support
1.6.3	ULPS exit: transmitted TWAKEUP interval
1.6.4	BTA: TX-Side TTA-GO interval value
1.6.5	BTA: RX-Side TTA-SURE interval value
1.6.6	BTA: RX-Side TTA-GET interval value
Probing configuration	Single-ended and differential acquisition
Triggering	Edge trigger for clock lane tests in clock continuous mode. Choice of width trigger and transition trigger for all other tests and all other modes
Reports	Excel xls, HTML, and MHT formats with zoom-in screen shots of the testing regions for each test

Datasheet

Receiver test specification

D-PHY base specification	Revision 1.2 and 2.0
D-PHY conformance specification	Revision 1.2 and 2.0
Group 1 tests	LP-RX voltage and timing requirement
2.1.1	LP-RX Logic 1 Input Voltage (VIH)
2.1.2	LP-RX Logic 0 Input Voltage, Non-ULP State (VIL)
2.1.4	LP-RX Input Hysteresis (VHYST)
2.1.5	LP-RX Minimum Pulse Width Response (TMIN-RX)
2.1.6	LP-RX Input Pulse Rejection (eSPIKE)
2.1.7	LP-RX Interference Tolerance (VINT and fINT)
Group 2 tests	LP-RX behavioral requirements
2.2.1	LP-RX Initialization period (TINIT)
2.2.2	ULPS Exit: LP-RX TWAKEUP Timer Value
2.2.3	Clock Lane LP-RX Invalid/Aborted ULPS Entry
2.2.4	Data Lane LP-RX Invalid/Aborted Escape Mode Entry
2.2.5	Data Lane LP-RX Invalid/Aborted Escape Mode Command
2.2.7	Data Lane LP-RX Escape Mode, Ignoring of Post-Trigger-Command Extra Bits
2.2.8	Data Lane LP-RX Escape Mode Unsupported/Unassigned Commands
Group 3 tests	HS-RX voltage and set up/hold requirements
2.3.1	HS-RX Common Mode Voltage Tolerance (VCMRX(DC))
2.3.2	HS-RX Differential Input High Threshold (VIDTH)
2.3.3	HS-RX Differential Input Low Threshold (VIDTL)
2.3.4	HS-RX Single-Ended Input High Voltage (VIHHS)
2.3.5	HS-RX Single-Ended Input Low Voltage (VILHS)
2.3.6	HS-RX Common-Mode Interference 50MHz - 450MHz (ΔVCMRX(LF))
2.3.7	HS-RX Common-Mode Interference Beyond 450MHz (ΔVCMRX(HF))
2.3.8	HS-RX Setup/Hold and Jitter Tolerance
2.3.9	HS-RX Setup/Hold and Jitter Tolerance (Spec 2.0, Data rate >=2.5Gbps)
Group 4 tests	HS-RX timer requirements
2.4.1	Data Lane HS-RX TD-TERM-EN Value
2.4.2	Data Lane HS-RX THS-PREPARE + THS-ZERO Tolerance
2.4.3	Data Lane HS-RX THS-SETTLE Value
2.4.4	Data Lane HS-RX THS-TRAIL Tolerance
2.4.5	Data Lane HS-RX THS-SKIP Value
2.4.6	Clock Lane HS-RX TCLK-TERM-EN Value
2.4.7	Clock Lane HS-RX TCLK-PREPARE + TCLK-ZERO Tolerance
2.4.8	Clock Lane HS-RX TCLK-SETTLE Value
2.4.9	Clock Lane HS-RX TCLK-TRAIL Tolerance
2.4.11	Clock Lane HS-RX TCLK-PRE and TCLK-POST Tolerance
Measurements	Both High Speed and Low Power modes, including ULPS and BTA.

Refer to MOI for detailed procedure.

Receiver test specification

D-PHY specification coverage

Standard	Specs version	Applicable SW options
D-PHY Transmitter	up to v1.2	D-PHYTX
D-PHY Receiver	up to v2.0	D-PHYXpress

Ordering Information

D-PHYTX Automated

Model	Description
DP07254/C DP07354/C MS070000/C DP070000B/C/DX/SX	DPO (Digital Phosphor Oscilloscope), MSO (Mixed Signal Oscilloscope) Oscilloscopes - 3.5 GHz and above is recommended Where rise time accuracies are not a concern, a 2.5 GHz oscilloscope can also be used.
TEKEXP	TekExpress [®] Automated Compliance Test Software
TEKEXP Opt. D-PHYTX	D-PHY Automated Solution for D-PHY Transmitter conformance, characterization, and verification Includes: Latest TekExpress product software DVD kit (P/N 020-2913-xx) and upgrade SW key. Online documentation and printable manual in PDF format are supplied.
TEKEXPUP Opt. D-PHYTX	D-PHY Automated Solution for D-PHY Transmitter conformance, characterization, and verification. Order this option if TekExpress (TEKEXP) is already owned. The USB key dongle will be upgraded with Opt. D-PHYTX. Includes: Latest TekExpress product software DVD kit (P/N 020-2913-xx) and upgrade SW key. Online documentation and printable manual in PDF format are supplied.

D-PHY Essentials

Model	Description
DPO7254/C DPO7354/C MSO70000/C DPO70000B/C/DX/SX	DPO (Digital Phosphor Oscilloscope), MSO (Mixed Signal Oscilloscope) Oscilloscopes - 3.5 GHz and above is recommended. Where rise time accuracies are not a concern, a 2.5 GHz oscilloscope can also be used.
DPO7254/C DPO7354/C MSO70000/C DPO70000B/C/DX/SX Opt. D-PHY ²	D-PHY Essentials for D-PHY Transmitter testing
DPO-UP Opt. D-PHY ²	D-PHY Essentials for D-PHY Transmitter testing upgrade
DPOFL-D-PHY ²	D-PHY Essentials for D-PHY Transmitter testing Upgrade (floating license version)
Model	Description
Termination board	1 x TMPC-CTB D-PHY Termination board

² Requires DPOJET Jitter and Eye Analysis Tools (Opt. DJA).

SR-DPHY Decode³

Model	Description
MSO/DPO5000 DPO7000C MSO70000C DPO70000C/D/SX Opt. SR-DPHY	MIPI [®] D-PHY Serial Analysis DSI-1 and CSI-2
DPO-UP Opt. SR-DPHY	MIPI [®] D-PHY Serial Analysis DSI-1 and CSI-2 upgrade
DPOFL-SR-DPHY	MIPI® D-PHY Serial Analysis DSI-1 and CSI-2 (floating license version)

Recommended probes for D-PHY Essentials or D-PHYTX Automated Solution

Oscilloscope	Probes
DP07000/C	4x TAP2500/TAP3500/P6245 ⁴ /P6249 ⁴ or 3x TDP3500 (Continuous clock) or 4x TDP3500 (Non-continuous clock)
	4x P7240 or 3x P7330/ P7340A/ P7360A/ P7380A/ P7313 (Continuous clock) or 4x P7330/ P7340A/ P7360A/ P7380A/ P7313 (Non-continuous clock) or 4x P7700 Series (D-PHY Essentials only)

D-PHY receiver setup

Model	Description
AWG70002A Options: 01/03/225 Option PRECOMFL-SS01 or PRECOMNL-SS01 on AWG	10 bit, 2 G Samples record length, 2-channel arbitrary waveform generator
AWGSYNC01DPO-UP	Hub for synchronizing multiple AWGs
TMPC-MDC4500-4B	MIPI signal conditioning accessory for the AWG 70000
DPO70000C with opt DJA and Probe (For calibration purpose)	6-8 GHz real-time scope, required for Calibration
DPHYNL-SSV1	D-PHY synthesis software on AWG
PSPL 5915 with Opt.100PS	100 ps Filter (SMA male-to SMA male)
174-6606-00	SMA cables
174-5771-xx	Phase-matched SMA cable

³ Requires Microsoft Windows 7 OS.

⁴ Requires TPA-BNC TekProbe2 to TekVPI adapter

Prerequisite host system software requirements for D-PHYTX Automated Solution for D-PHY Transmitter Conformance, Characterization, and Verification

Includes: Latest TekExpress product software DVD kit (P/N 020-2913-xx) and upgrade SW key. Online documentation and printable manual in PDF format are supplied D-PHY Automated Solution for D-PHY Transmitter Conformance, Characterization, and Verification. Order this option if TekExpress (TEKEXP) is already owned. The USB key dongle will be upgraded with Opt. D-PHYTX

Includes: Latest TekExpress product software DVD kit (P/N 020-2913-xx) and upgrade SW key. Online documentation and printable manual in PDF format are D-PHYTX

- Microsoft XP OS with SP2 or later, or Windows 7
- Microsoft Excel 2002 or above
- Microsoft Explorer 6.0 SP1 or later
- Adobe Reader 6.0 or equivalent software for viewing portable document format (PDF) files



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Product(s) complies with IEEE Standard 488.1-1987, RS-232-C, and with Tektronix Standard Codes and Formats

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* European toll-free number. If not accessible, call: +41 52 675 3777

For Further Information. Tektronix maintains a comprehensive, constantly expanding collection of application notes, technical briefs and other resources to help engineers working on the cutting edge of technology. Please visit www.tek.com

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